GAGING STANDS

VERSATILE, NON-DEDICATED GAGE
FIXTURING FOR MANY MEASUREMENT APPLICATIONS





Brunswick Instrument

Sharing your commitment to quality

Brunswick's selection of comparator stands are designed to provide the stability and durable accuracy needed for electronic gaging. All are suited for use with mechanical indicators as well.

All models have heavy bases, backlash free vertical fine adjustment and plated posts.

MODEL 159F COMPARATOR STAND - The

Model 159F Comparator Stand features measuring height capacity to 8", throat depth of 3-3/4" and 1/8" of vertical fine adjustment. The 3/8" diameter mounting bore allows cartridge style gage probes or AGD standard dial indicators to be easily interchanged. The anvil provided is a flat, ground and lapped disc measuring 3-5/8" in diameter. Weight is 15 lbs.

MODEL 159S COMPARATOR STAND - The

Model 159S Comparator Stand is identical to the Model 159F described above except is supplied with a ground and lapped anvil having a serrated surface.

MODEL 258 COMPARATOR STAND - The

Model 258 Comparator Stand is a larger, heavier unit for ultra-precise inspection work. It features measuring height capacity to 8", throat depth of 4" and 1/4" of vertical fine adjustment. The 3/8" diameter mounting bore allows cartridge style gage probes or AGD standard dial indicators to be easily interchanged. The supplied reversible anvil has both flat and serrated surfaces and measures 1-1/2" wide by 3" deep. Weight is 29 lbs.

MODEL 258D DUAL PROBE

COMPARATOR STAND - The Model 258D Dual Probe Comparator Stand incorporates all the features of the standard Model 258 except for a special purpose anvil design. The special anvil allows a second electronic cartridge probe to be mounted inside the anvil itself providing the means to contact a part from below as well as above for improved thickness gaging. A multiple input gage amplifier such as the Brunswick MP-2,4,or 8 Metrology Processor, that can sum the measurement values of both probes, may be used to achieve thickness, diameter and parallelism measurements with a higher degree of accuracy than a single probe system can provide. The flat anvil surface measures 3" square.

CUSTOM DESIGNS ALSO AVAILABLE -

Specially designed dual-probe stands are available in granite or steel as shown. Various sizes and shapes of bases can be made to order.



